# DISCRETE SEMICONDUCTORS



Product specification Supersedes data of April 1996 File under Discrete Semiconductors, SC01 1996 Sep 03



## 1N4150; 1N4151; 1N4153

### FEATURES

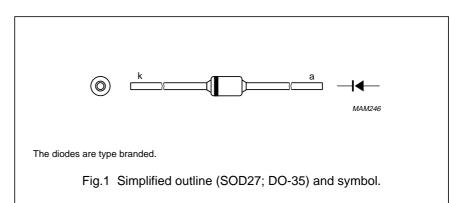
- Hermetically sealed leaded glass SOD27 (DO-35) package
- High switching speed: max. 4 ns
- General application
- Continuous reverse voltage: max. 50 V
- Repetitive peak reverse voltage: max. 75 V
- Repetitive peak forward current: max. 600 mA and 450 mA respectively.

### **APPLICATIONS**

- High-speed switching
- 1N4150: general purpose use in computer and industrial applications
- 1N4151 and 1N4153: military and industrial applications.

### DESCRIPTION

The 1N4150, 1N4151, 1N4153 are high-speed switching diodes fabricated in planar technology, and encapsulated in hermetically sealed leaded glass SOD27 (DO-35) packages.



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### LIMITING VALUES

In accordance with the Absolute Maximum Rating System (IEC 134).

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
V <sub>RRM</sub>	repetitive peak reverse voltage				
	1N4151		_	75	V
	1N4153		_	75	V
V <sub>R</sub>	continuous reverse voltage		_	50	V
IF	continuous forward current	see Fig.2; note 1			
	1N4150		_	300	mA
	1N4151		_	200	mA
	1N4153		_	200	mA
I <sub>FRM</sub>	repetitive peak forward current				
	1N4150		_	600	mA
	1N4151		_	450	mA
	1N4153		_	450	mA
I <sub>FSM</sub>	non-repetitive peak forward current	square wave; T <sub>j</sub> = 25 °C prior to surge; see Fig.4			
		t = 1 μs	_	4	A
		t = 1 ms	_	1	A
		t = 1 s	_	0.5	А
P <sub>tot</sub>	total power dissipation	T <sub>amb</sub> = 25 °C; note 1	_	500	mW
T <sub>stg</sub>	storage temperature		-65	+200	°C
Tj	junction temperature		_	200	°C

### Note

1. Device mounted on an FR4 printed-circuit board; lead length 10 mm.

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### **ELECTRICAL CHARACTERISTICS**

 $T_j = 25 \ ^{\circ}C$ ; unless otherwise specified.

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
V <sub>F</sub>	forward voltage	see Fig.3			
	1N4150	I <sub>F</sub> = 1 mA	540	620	mV
		I <sub>F</sub> = 10 mA	660	740	mV
		I <sub>F</sub> = 50 mA	760	860	mV
		I <sub>F</sub> = 100 mA	820	920	mV
		I <sub>F</sub> = 200 mA	870	1000	mV
	1N4151	I <sub>F</sub> = 50 mA	-	1000	mV
	1N4153	I <sub>F</sub> = 0.1 mA	490	550	mV
		I <sub>F</sub> = 0.25 mA	530	590	mV
		I <sub>F</sub> = 1 mA	590	670	mV
		$I_F = 2 \text{ mA}$	620	700	mV
		I <sub>F</sub> = 10 mA	700	810	mV
		I <sub>F</sub> = 50 mA	740	880	mV
I <sub>R</sub>	reverse current	V <sub>R</sub> = 50 V; see Fig.5			
	1N4150		-	0.1	μA
	1N4151		_	0.05	μA
	1N4153		-	0.05	μA
I <sub>R</sub>	reverse current	V <sub>R</sub> = 50 V; T <sub>j</sub> = 150 °C; see Fig.5			
	1N4150		-	100	μA
	1N4151		_	50	μA
	1N4153		_	50	μA
C <sub>d</sub>	diode capacitance	$f = 1 \text{ MHz}; V_R = 0; \text{ see Fig.6}$			
	1N4150		-	2.5	pF
	1N4151		_	2	pF
	1N4153			2	pF

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SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
t <sub>rr</sub>	reverse recovery time 1N4150	when switched from $I_F = 10$ mA to $I_R = 1$ mA; $R_L = 100 \Omega$ ; measured at $I_R = 0.1$ mA; see Fig.7	_	6	ns
		when switched from $I_F = 10$ mA to 200 mA to $I_R = 10$ mA to 200 mA; $R_L = 100 \Omega$ ; measured at $I_R = 0.1 \times I_F$ ; see Fig.7	_	4	ns
		when switched from $I_F$ = 200 mA to 400 mA to $I_R$ = 200 mA to 400 mA; $R_L$ = 100 $\Omega$ ; measured at $I_R$ = 0.1 × $I_F$ ; see Fig.7	_	6	ns
t <sub>rr</sub>	reverse recovery time 1N4151	when switched from $I_F = 10$ mA to $I_R = 10$ mA; $R_L = 100 \Omega$ ; measured at $I_R = 1$ mA; see Fig.7	_	4	ns
		when switched from $I_F = 10$ mA to $I_R = 60$ mA; $R_L = 100 \Omega$ ; measured at $I_R = 1$ mA; see Fig.7	-	2	ns
t <sub>rr</sub>	reverse recovery time 1N4153	when switched from $I_F = 10$ mA to $I_R = 10$ mA; $R_L = 100 \Omega$ ; measured at $I_R = 1$ mA; see Fig.7	_	4	ns
		when switched from $I_F = 10$ mA to $I_R = 60$ mA; $R_L = 100 \Omega$ ; measured at $I_R = 1$ mA; see Fig.7	-	2	ns
t <sub>fr</sub>	forward recovery time	when switched to $I_F = 200 \text{ mA}$ ; $t_r = 0.4 \text{ ns}$ ; measured at $V_F = 1 \text{ V}$ ; see Fig.8	_	10	ns

### THERMAL CHARACTERISTICS

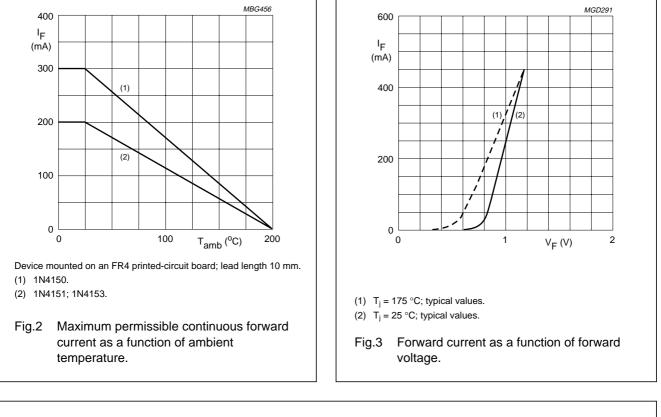
SYMBOL	PARAMETER	CONDITIONS	VALUE	UNIT
R <sub>th j-tp</sub>	thermal resistance from junction to tie-point	lead length 10 mm	240	K/W
R <sub>th j-a</sub>	thermal resistance from junction to ambient	lead length 10 mm; note 1	350	K/W

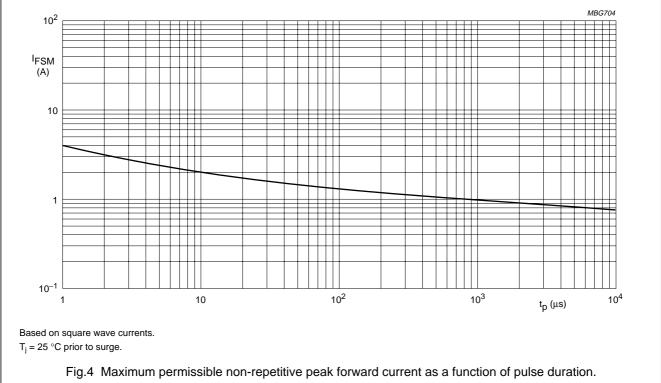
Note

1. Device mounted on a printed circuit-board without metallization pad.

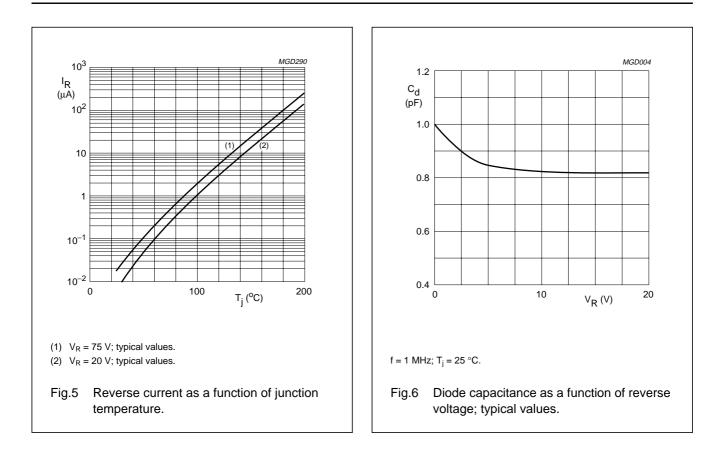
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### **GRAPHICAL DATA**

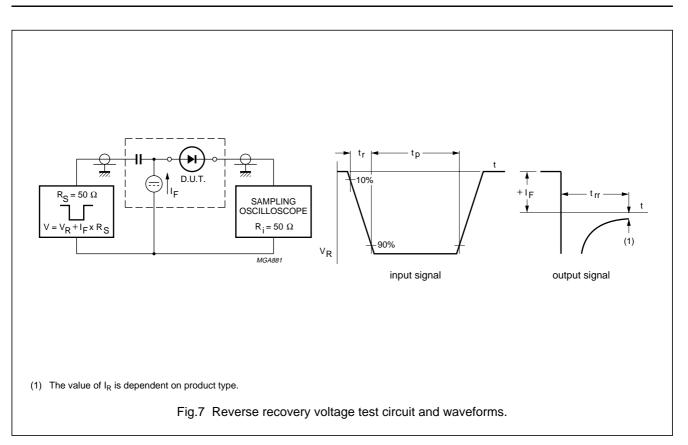


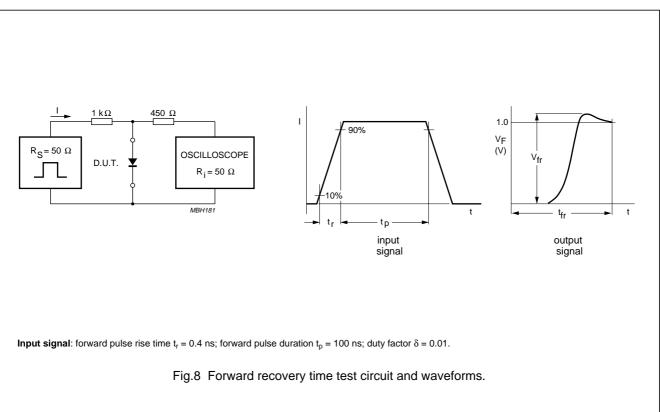


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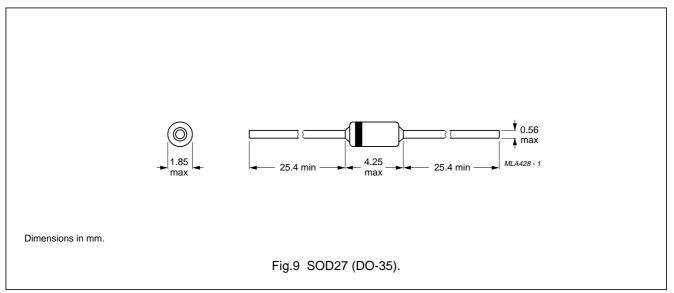
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### PACKAGE OUTLINE



#### DEFINITIONS

Data Sheet Status				
Objective specification This data sheet contains target or goal specifications for product development.				
Preliminary specification	This data sheet contains preliminary data; supplementary data may be published later.			
Product specification	This data sheet contains final product specifications.			
Limiting values				
Limiting values given are in accordance with the Absolute Maximum Rating System (IEC 134). Stress above one or more of the limiting values may cause permanent damage to the device. These are stress ratings only and operation of the device at these or at any other conditions above those given in the Characteristics sections of the specification is not implied. Exposure to limiting values for extended periods may affect device reliability.				
Application information				
Where application information is given, it is advisory and does not form part of the specification.				
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### LIFE SUPPORT APPLICATIONS

These products are not designed for use in life support appliances, devices, or systems where malfunction of these products can reasonably be expected to result in personal injury. Philips customers using or selling these products for use in such applications do so at their own risk and agree to fully indemnify Philips for any damages resulting from such improper use or sale.